

Problem/Failure Report THM_PFR_169

		E Damage to Ion Detectors	
Assembly: SST		SubAssembly: Sensor	
Component : Detector		Units Affected:	Units fixed:
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Failure Occurred During			
□ Functional test □ Qualificat	-	ration Launch operation	ns X Other (Calibration)
Environment when failu			
	bration	□ Shock	□ Acoustic
□ Thermal X V	acuum	☐ Thermal-Vacuum	□ EMI/EMC
(In this section it is important to		Description	
happen again, we would like to Poor instrument performance in Only ion detectors on DFE boa calibration once discovered.	n ion detectors. Units	affected are SEA-14-10 a	
Ar (How do we know how the failu	· ·	d to Determine Caus a bad part, bad handling,	
During electron calibration, pla that damaged ion detectors that Electron detectors showed no d	happened to be in the	e field of view. Results w	
		tion/ Resolution	
(How do we fix the unit? And h Electron gun refurbished and el affected DFE boards were repla	ectron calibrations on		tectors covered. Detectors on
Acceptance: MAM: Ron Jackson	; I	MSE: Ellen Taylor	
		a	
PM: Peter Harvey	: (Jognizant Engineer	